

 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				Atty. Docket No. 14657			Serial No. 10/811,153
LIST OF PRIOR ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Lu			
				FILING DATE 3/29/04		GROUP 1774	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CF	AA	US 2002 0093006A1	7/18/02	Vardeny et al.			
	AB	US 2003 0042846A1	3/6/03	Forrest et al.			
	AC	4356429	10/26/82	Tang			
	AD	5171373	12/15/92	Hebard et al.			
	AE	5759725	6/2/98	Hirao et al.			
	AF	5776622	7/7/98	Hung et al.			
	AG	5861219	1/19/99	Thompson et al.			
	AH	6310360	10/30/01	Forrest et al.			
CF	AI	6486601	11/26/02	Sakai et al.			
CF	AJ	6515298	2/4/03	Forrest et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
CF	AK	WO 02 058110 A2	7/25/02	International			X
CF	AL	JP 5331458	12/14/93	Japan			abstract in English
CF	AM	JP04-144479	1992	Japan			abstract in English
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
CF	AN	Metal/AlQ ₃ Interface Structures, Turak et al., Applied Physics Letters, Vol. 81, No. 4, 22 July 2002, 766-768					
CF	AO	Organic Light-Emitting diodes with a Nanostructured Fullerene Layer at the Interface between Alq ₃ and TPD Layers, Kato et al., Jpn. J. Appl. Phys. Vol. 42 (2003) pp 2526-2529, Part 1. No. 4B, April 2003					
EXAMINER	J. M. Bm	DATE CONSIDERED	5/04				
<small>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

FORM PTO-1449 (Rev. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			Atty. Docket No. 14657		Serial No. 10/811,153		
O I P E LIS OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Lu et al.				
					FILING DATE 03/29/2004		GROUP 1774		
<i>EXAMINER TRADEMARK OFFICE</i>		U.S. PATENT DOCUMENTS							
		INITIAL	DOCUMENT NUMBER		DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		AA							
		AB							
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FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
<i>AF</i>	AL	WO 02/058110 A2 and A3	7/25/2002	International			YES <input checked="" type="checkbox"/> NO <input type="checkbox"/>		
	AM								
	AN								
	AO								
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)									
	AP								
	AQ								
EXAMINER	<i>J. Ferguson</i>		DATE CONSIDERED	<i>5/8/04</i>					
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APPLICANT Lu et al.

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GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER								DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CF	AA	5	8	6	1	2	1	9	01/19/99					
	AB	5	7	5	9	7	2	5	06/02/98					
	AC	5	7	7	6	6	2	2	07/07/98					
	AD	6	5	1	5	2	9	8	02/04/03					
	AE	6	4	8	6	6	0	1	11/26/02					
	AF	6	3	1	0	3	6	0	10/30/01					
	AG	2002/0093006								07/18/02				
	AH	2003/0042846								03/06/03				
	AI	4	3	5	6	4	2	9	10/26/82					
✓	AJ	5	1	7	1	3	7	3	12/15/92					
	AK													

FOREIGN PATENT DOCUMENTS

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														YES	NO
	AL														
	AM														
	AN														
	AO														

OTHER PRIOR ART (including Author, Title, Date, Pertinent Pages, Etc.)

CF	AP		"Metal/AlQ ₃ Interface Structures", Turak et al. Applied Physics Letters, July 22, 2002, Vol. 81(4), pp 766-768.
CF	AQ		"Organic Light-Emitting Diodes with a Nanostructured Fullerene Layer at the Interface between Alq ₃ an TPD Layers", Kato et al.; Jpn. J. Appl Phys, April 2003, Vol. 42(2003), pp 2526-2529.

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5/10/04

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